LATS2015

16th IEEE Latin-American Test Symposium

Puerto Vallarta, Mexico, March 25th - 27th, 2015

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CALL FOR PAPERS

The IEEE Latin-American Test Symposium (LATS, previously Latin-American Test Workshop - LATW) is a recognized forum for test and fault tolerance professionals and technologists from all over the world, in particular from Latin America, to present and discuss various aspects of system, board, and component testing and fault-tolerance with design, manufacturing and field considerations in mind. Presented papers are also published in the IEEE Xplore Digital Library. The best papers of the 16th LATS will be invited to re-submit to the IEEE Design and Test of Computers, IEEE Transactions on Computer-Aided Design, Journal of Electronic Testing: Theory and Applications - JETTA (Springer) and Journal of Low Power Electronics - JOLPE (American Scientific Publishers).

Topics of interest include but are not limited to:

- Analog Mixed Signal Test
- Automatic Test Generation
- Built-In Self-Test
- Defect-Based Test
- Design and Synthesis for Testability
- Design for Electromagnetic Compatibility
- Design for Reliable Embedded Software
- Design Verification/Validation
- Economics of Test
- Fault Analysis and Diagnosis
- Fault Modeling and Simulation
- Fault-Tolerance in HW/SW
- Fault-Tolerant Architectures
- Hardware Trust & Security Approaches
- HW-SW Integrity Checking to Prevent Attacks
- Memory Test and Repair
- On-Line Testing
- Process Control and Measurements
- Radiation/EMI
- Software Fault-Tolerance
- Software On-Line Testing
- System-on-Chip Test
- Yield Optimization

Paper Submission Information:

To encourage and facilitate discussions, participation will be limited. Those interested in presenting recent results at the symposium are invited to submit an extended abstract, one to three pages long, or a full length paper. PDF electronic submissions should be done via the symposium webpage: *latS.tttc-events.org*

Authors should send papers in the IEEE format. Detailed instructions are available at the symposium webpage. The Program Committee also welcomes proposals for panels and special topic sessions.

For additional information, please contact one of the Program Chairs:
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Vishwani Agrawal – Auburn University, United States of America:
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Submission Deadline: November 14th, 2014.
Notification of Acceptance: December 19th, 2014.
Camera Ready: January 16th, 2015.

LATS 2015 will take place in Puerto Vallarta, Mexico. This beautiful city is also a resort beach located in the Pacific Ocean. This place is surrounded by the mountains of Sierra Madre Occidental and the sparkling blue Bahía de Banderas (Bay of Flags). The sun-kissed beach resort embraces the coast of Jalisco state. Once a small village where fishing and pearl-diving were the order of the day, Puerto Vallarta is now a tourist attraction. With ideal weather, picturesque beaches and colonial cobblestone streets make this a perfect holiday destination.

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